

EE 330

Lecture 16

Devices in Semiconductor Processes

- MOSFETs

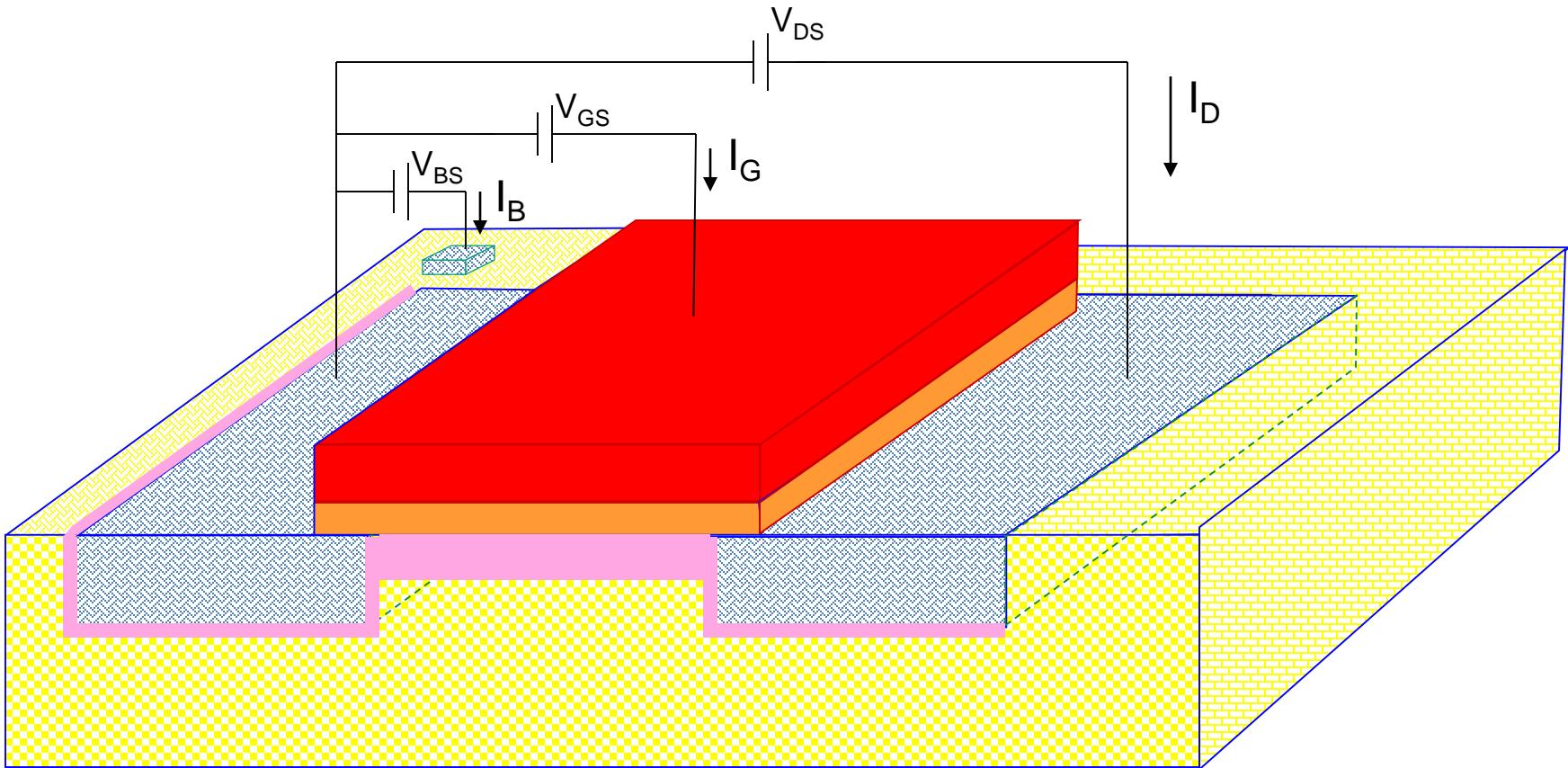
Basic Devices and Device Models

- Resistor
- Diode
- Capacitor

 MOSFET

- BJT

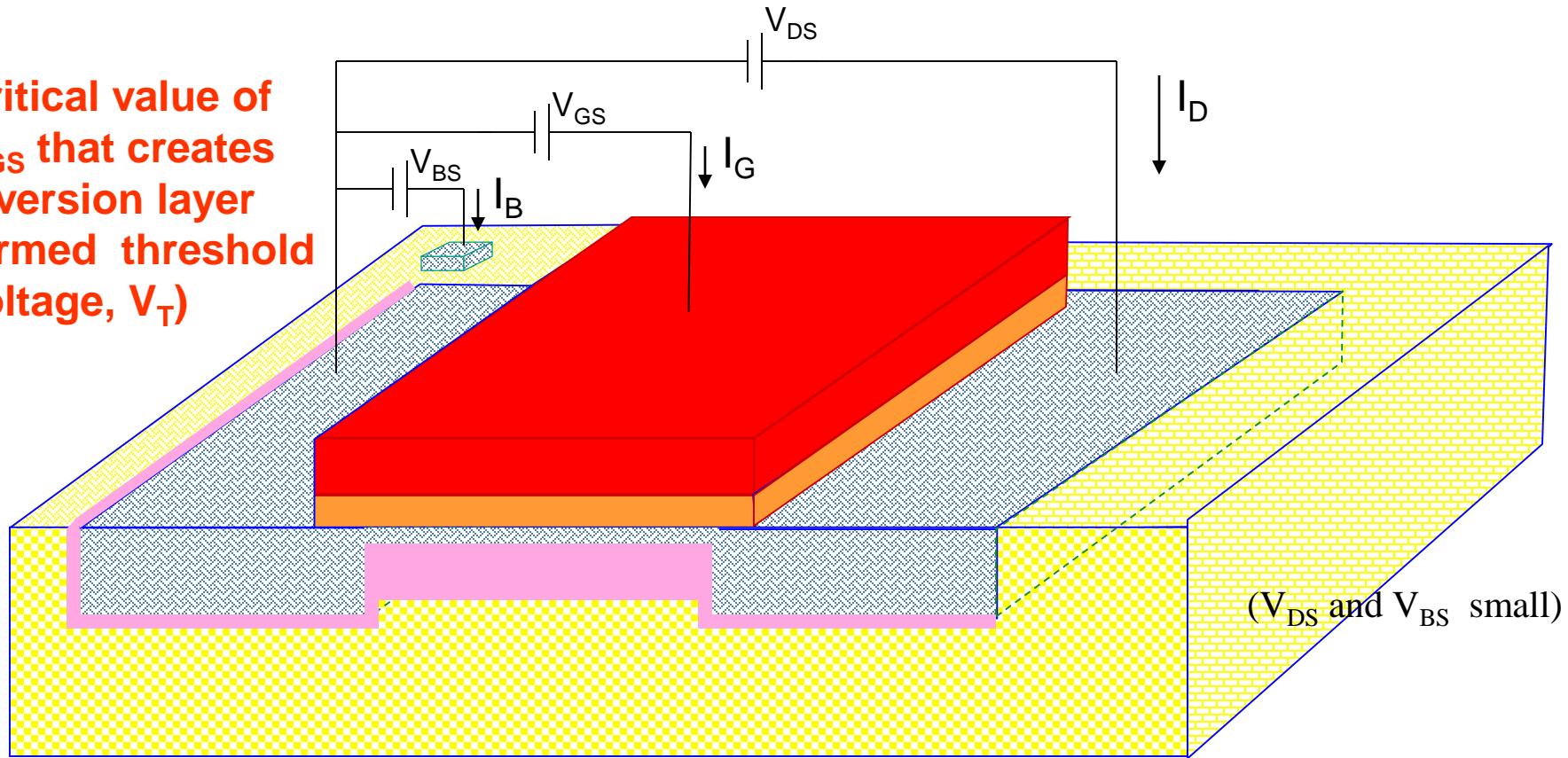
n-Channel MOSFET Operation and Model



$$\boxed{\begin{aligned} I_D &= 0 \\ I_G &= 0 \\ I_B &= 0 \end{aligned}}$$

Model in Cutoff Region

n-Channel MOSFET Operation and Model



Increase V_{GS} more

Inversion layer forms in channel

Inversion layer will support current flow from D to S

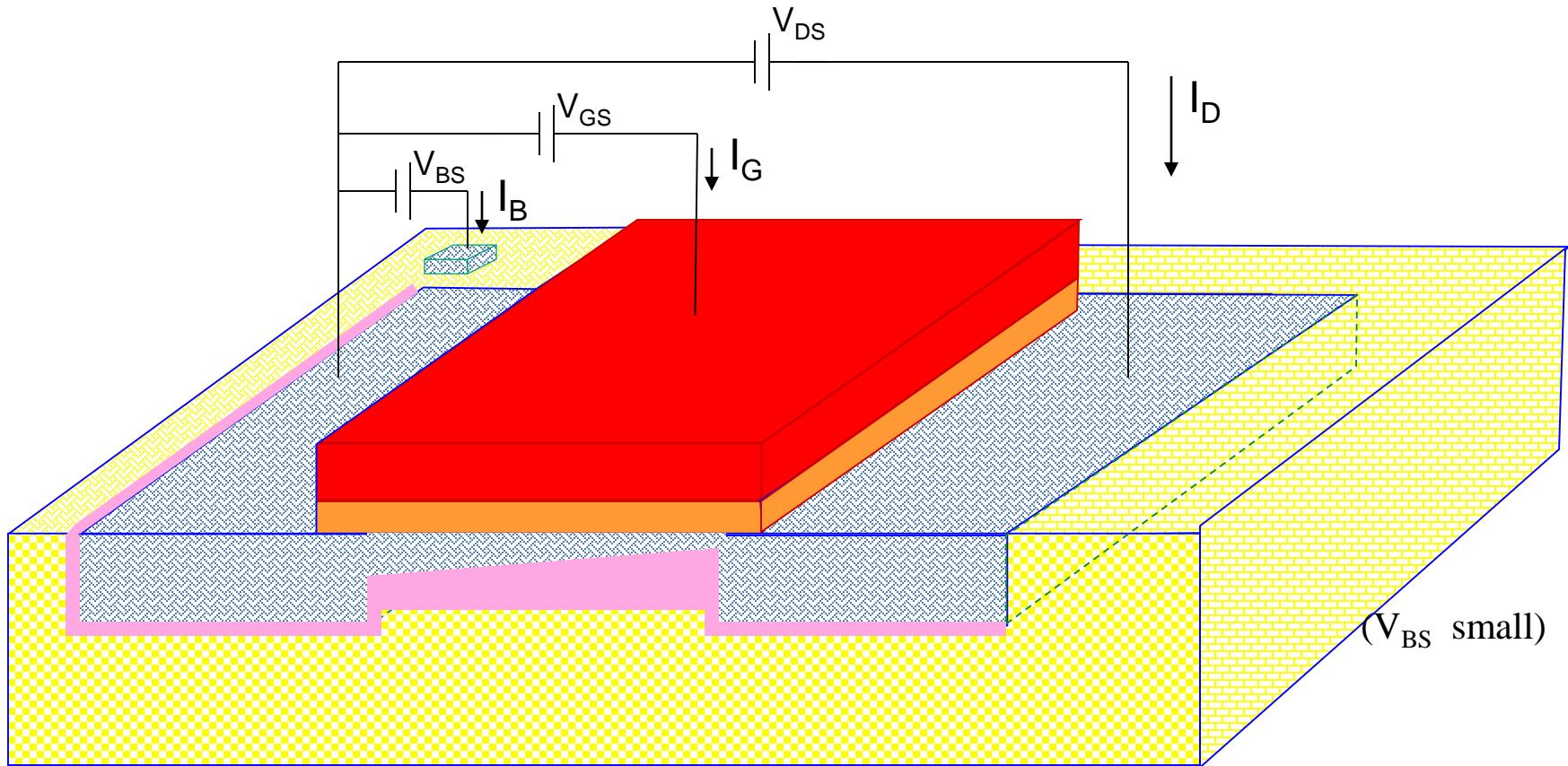
Channel behaves as thin-film resistor

$$I_D R_{CH} = V_{DS}$$

$$I_G = 0$$

$$I_B = 0$$

n-Channel MOSFET Operation and Model



Increase V_{DS}

Inversion layer thins near drain

I_D no longer linearly dependent upon V_{DS}

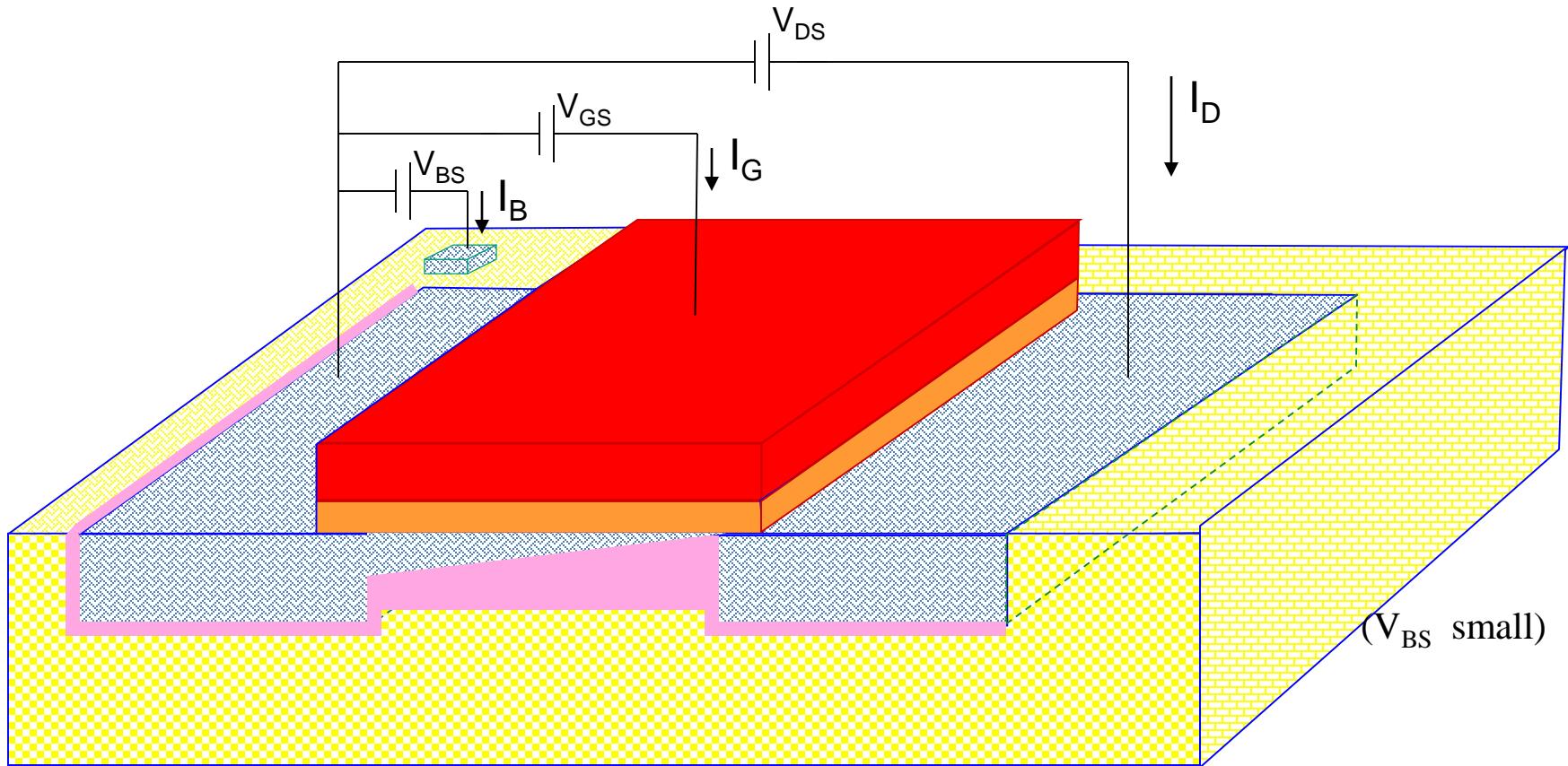
Still termed “ohmic” or “triode” region of operation

$$I_D = ?$$

$$I_G = 0$$

$$I_B = 0$$

n-Channel MOSFET Operation and Model



Increase V_{DS} even more

Inversion layer disappears near drain

Termed “saturation”region of operation

Saturation first occurs when $V_{DS}=V_{GS}-V_T$

$$I_D = ?$$

$$I_G = 0$$

$$I_B = 0$$

Model Summary

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

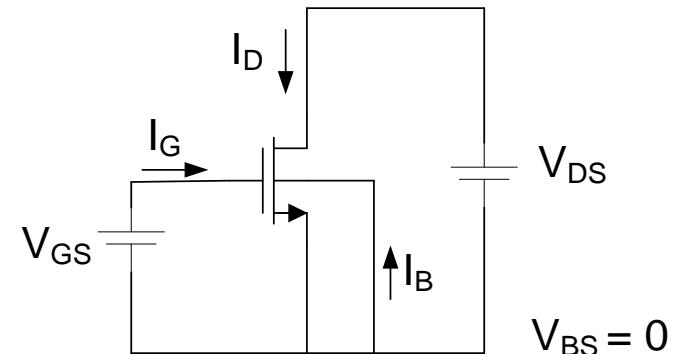
$$I_G = I_B = 0$$

This is a piecewise model (not piecewise linear though)

Note: This is the third model we have introduced for the MOSFET

(Deep triode special case of triode where V_{DS} is small

$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_T) \mu C_{ox}})$$



$$V_{GS} \leq V_T$$

Cutoff

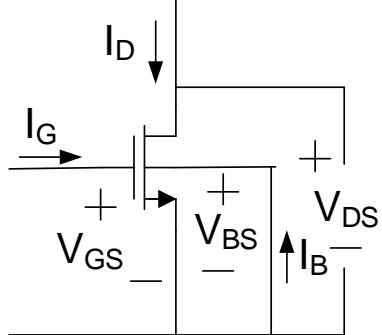
$$V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T$$

Triode

$$V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T$$

Saturation

Model Summary



$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$I_G = I_B = 0$$

Observations about this model (developed for $V_{BS}=0$):

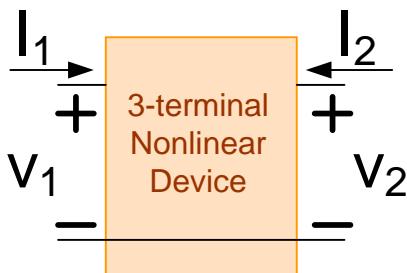
$$I_D = f_1(V_{GS}, V_{DS})$$

$$I_G = f_2(V_{GS}, V_{DS})$$

$$I_B = f_3(V_{GS}, V_{DS})$$

This is a nonlinear model characterized by the functions f_1 , f_2 , and f_3 where we have assumed that the port voltages V_{GS} and V_{DS} are the independent variables and the drain currents are the dependent variables

General Nonlinear Model

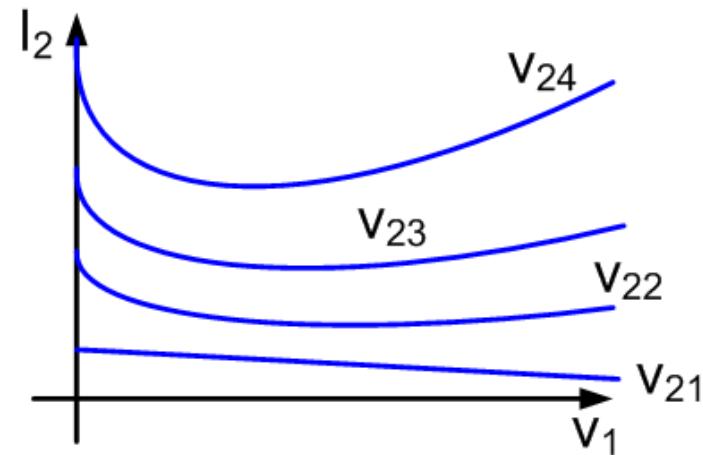
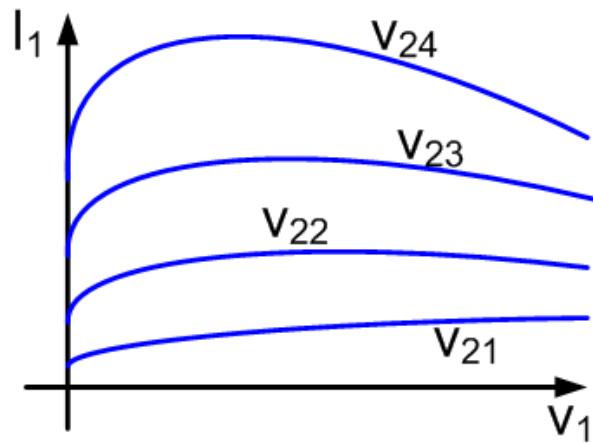


$$I_1 = f_1(V_1, V_2)$$

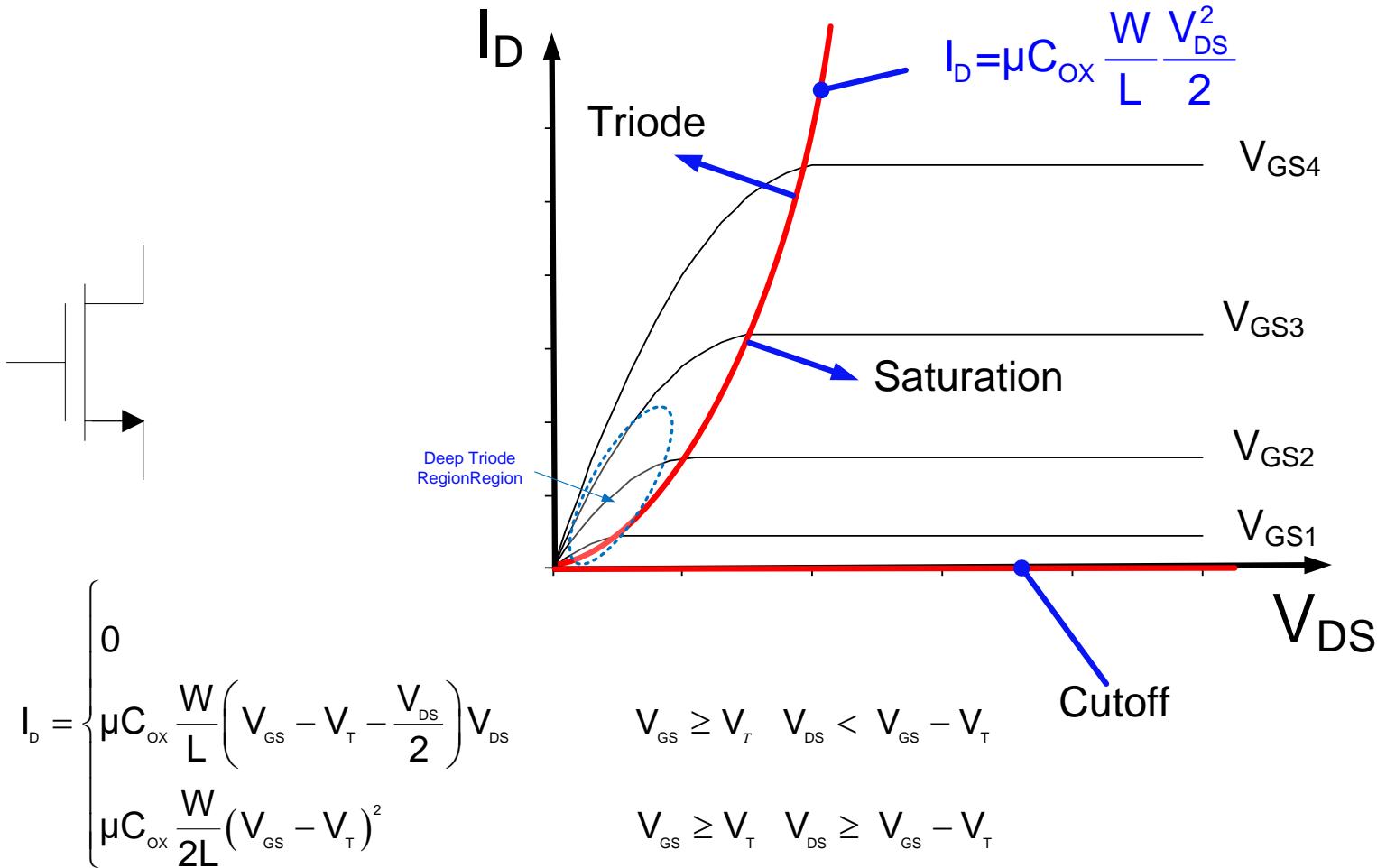
$$I_2 = f_2(V_1, V_2)$$

I_1 and I_2 are 3-dimensional relationships which are often difficult to visualize

Two-dimensional representation of 3-dimensional relationships

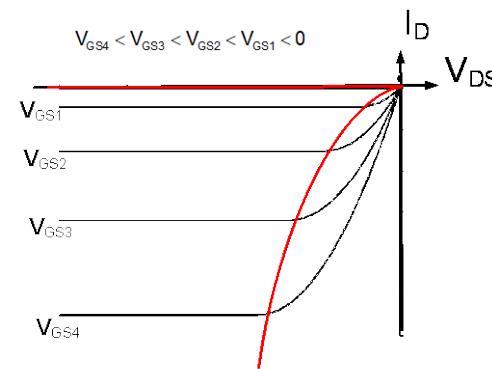
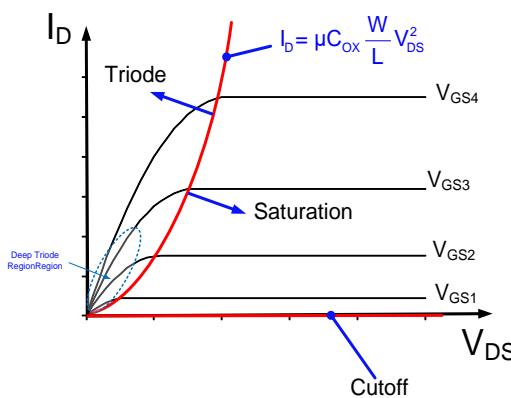
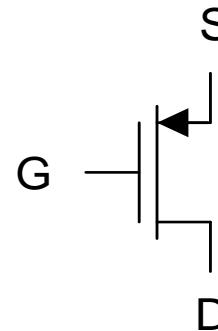
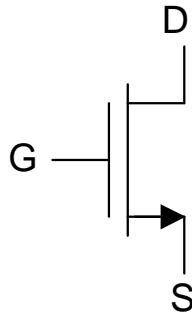


Graphical Representation of MOS Model



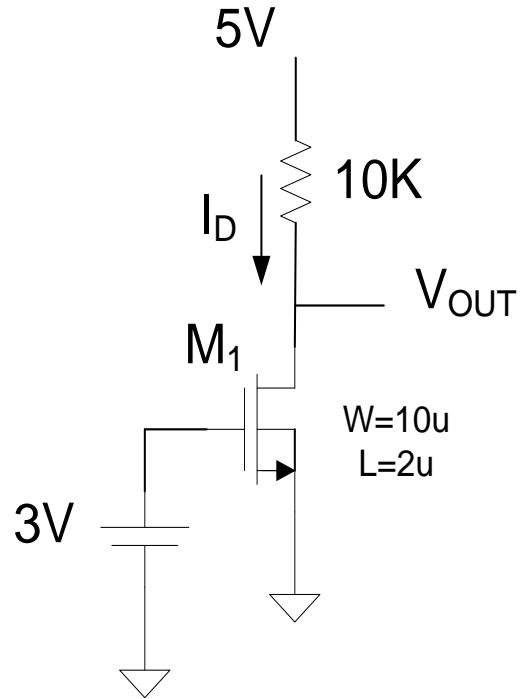
$$I_G = I_B = 0$$

PMOS and NMOS Models



- Functional form identical, sign changes and parameter values different
- Will give details about p-channel model later

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu A V^{-2}$

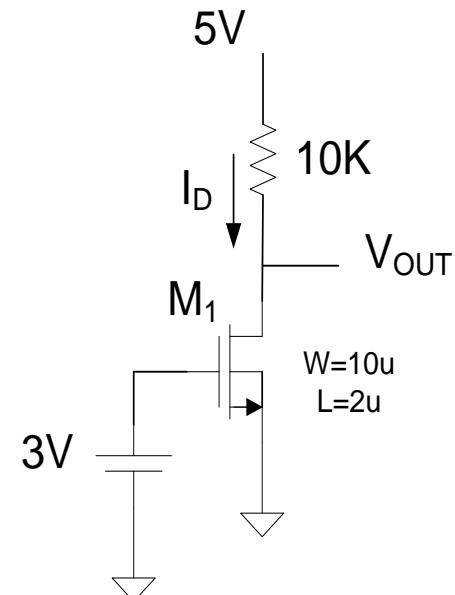


Solution:

Since $V_{GS} > V_T$, M_1 is operating in either saturation or triode region

Strategy will be to guess region of operation, solve, and then verify region

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu A V^{-2}$



Solution:

Guess M₁ in saturation

$$\left. \begin{array}{l} 5V = I_D 10K + V_{OUT} \\ I_D = \frac{\mu C_{OX} W}{2L} (3 - V_T)^2 \end{array} \right\}$$

Required verification: $V_{DS} > V_{GS} - V_T$

Can eliminate I_D between these 2 equations to obtain V_{OUT}

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu A V^{-2}$

Guess M_1 in saturation

$$\left. \begin{array}{l} 5V = I_D 10K + V_{OUT} \\ I_D = \frac{\mu C_{OX} W}{2L} (3 - V_T)^2 \end{array} \right\}$$

Required verification: $V_{DS} > V_{GS} - V_T$

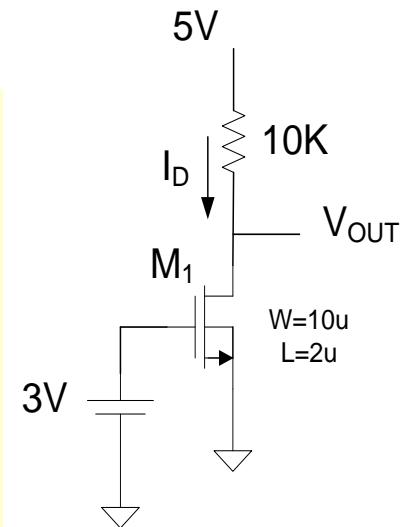
$$V_{OUT} = 5V - 10K \left[\frac{100\mu A V^{-2} 10\mu}{2 \cdot 2\mu} (2V)^2 \right]$$

$$V_{OUT} = 5V - 10K \left[\frac{100\mu A V^{-2} 10\mu}{2 \cdot 2\mu} (2V)^2 \right]$$

$$V_{OUT} = -5V$$

Verification: $V_{DS} = V_{OUT}$

$-5 >? 2V - - 0$ No! So verification fails and Guess of region is invalid



Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu A V^{-2}$

Guess M_1 in triode

$$5V = I_D 10K + V_{OUT}$$

$$I_D = \frac{\mu C_{OX} W}{L} \left(3 - V_T - \frac{V_{DS}}{2} \right) V_{DS} \quad \left. \right\}$$

$$V_{OUT} = 5V - 10K \left[\frac{100\mu A V^{-2} 10\mu}{2\mu} \left(2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

$$V_{OUT} = 5V \left[5 \left(2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

Solving for V_{OUT} , obtain

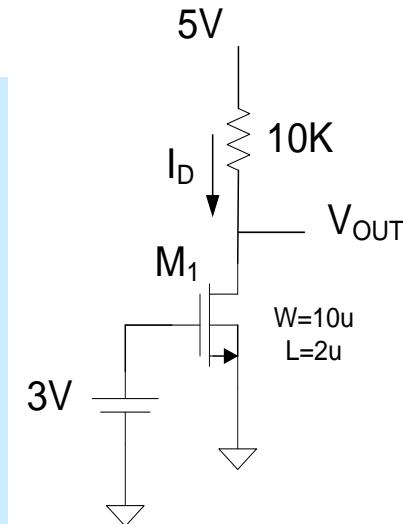
$$V_{OUT} = 0.515V$$

Verification: $V_{DS} = V_{OUT}$

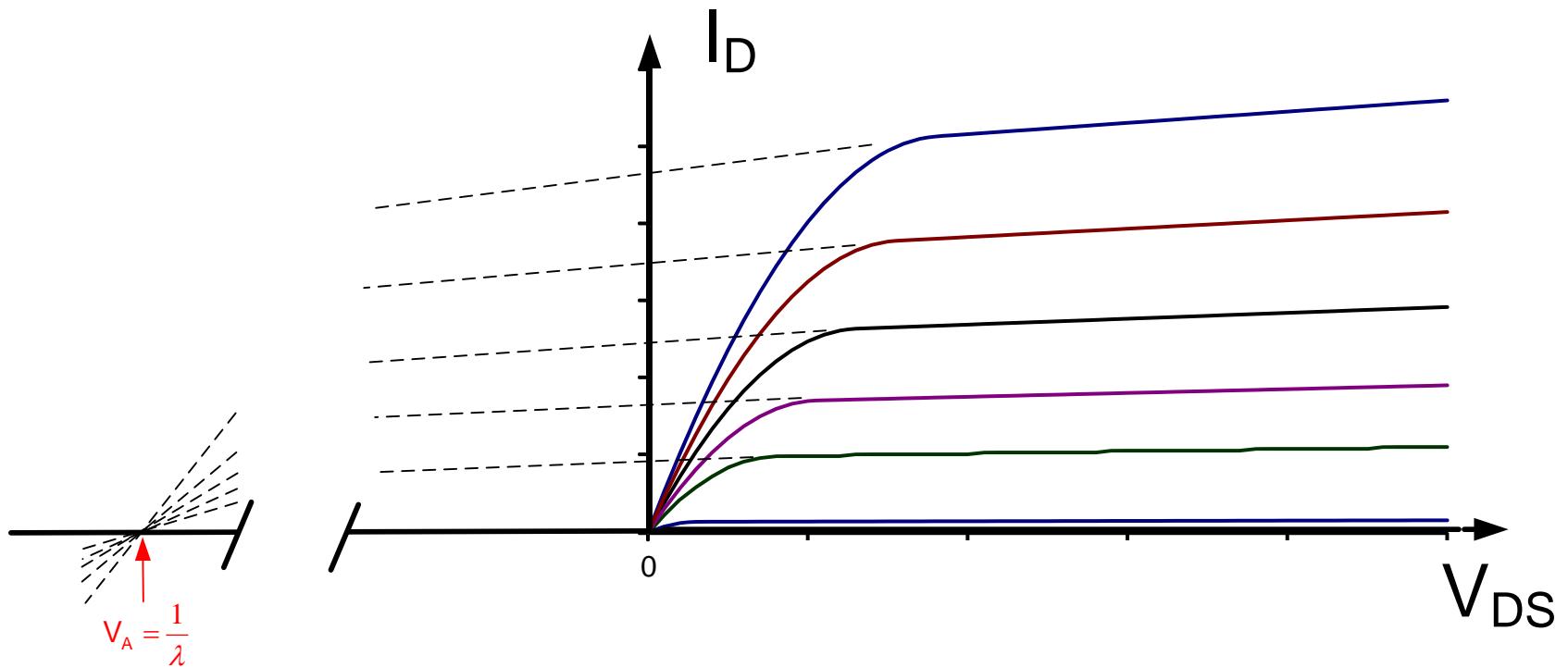
$0.515 < ? 2V - - 0$ Yes!

So verification succeeds and triode region is valid

$V_{OUT} = 0.515V$



Model Extensions

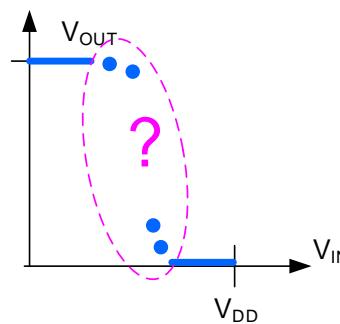
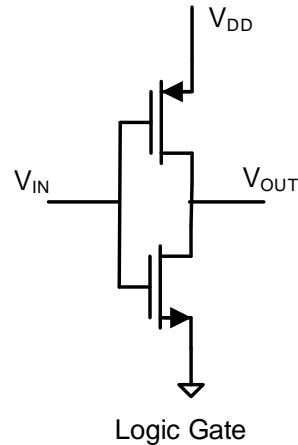


Projections intersect $-V_{DS}$ axis at same point, termed Early Voltage

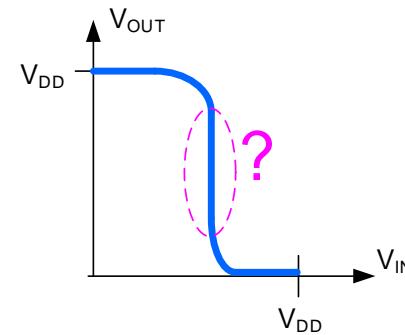
Typical values from -20V to -200V

Usually use parameter λ instead of V_A in MOS model

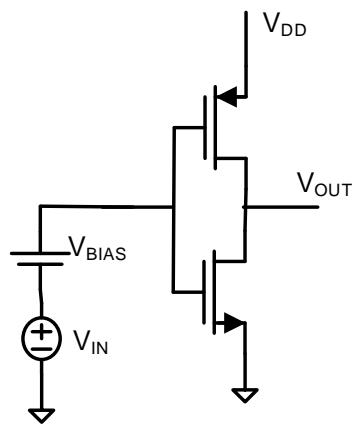
Limitations of Existing Models



Switch-Level Models



Simple square-law Model



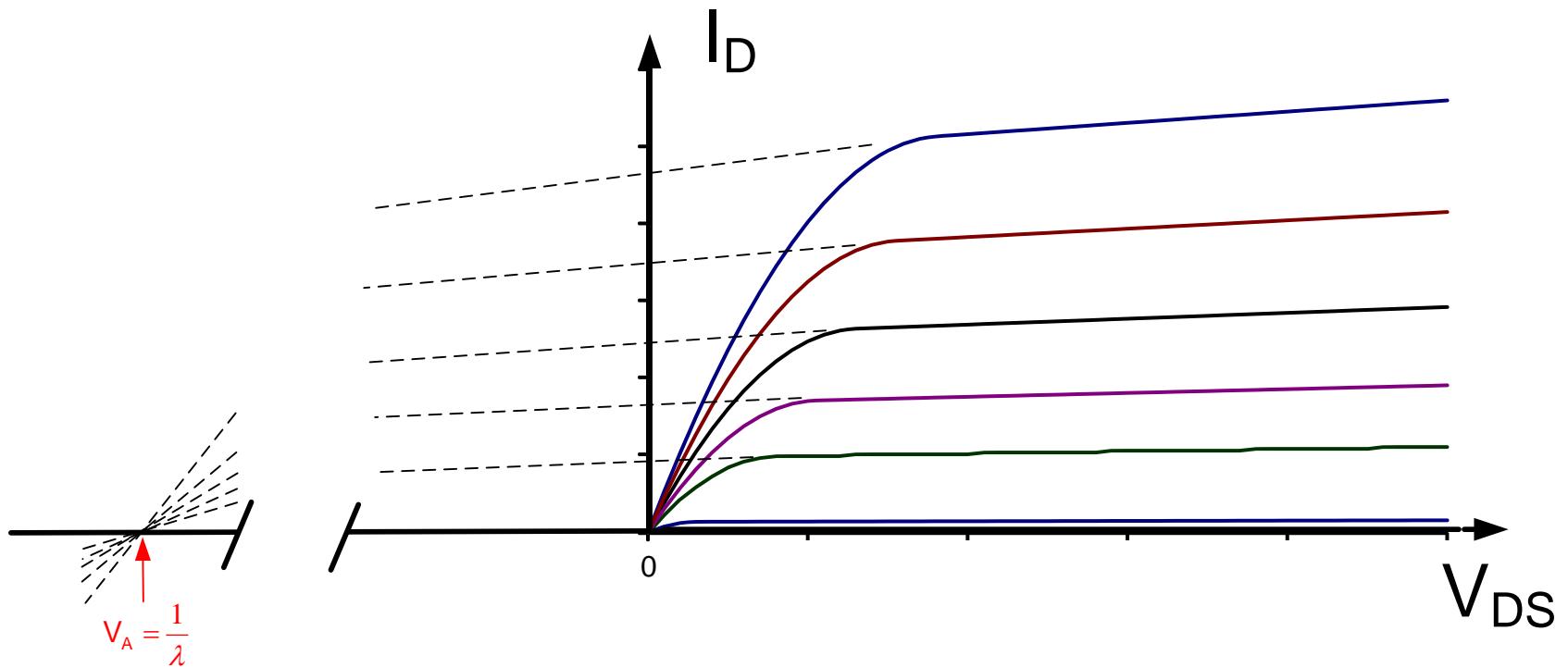
Voltage Amplifier

Switch-Level Models
Simple square-law Model

Voltage Gain
Input/Output Relationship

?

Model Extensions

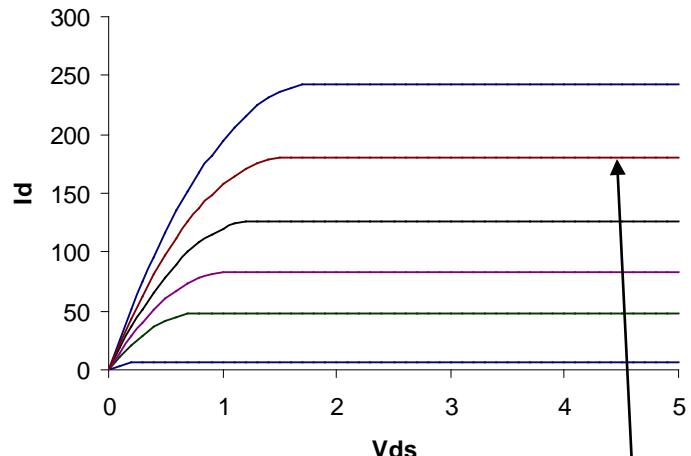


Projections intersect $-V_{DS}$ axis at same point, termed Early Voltage

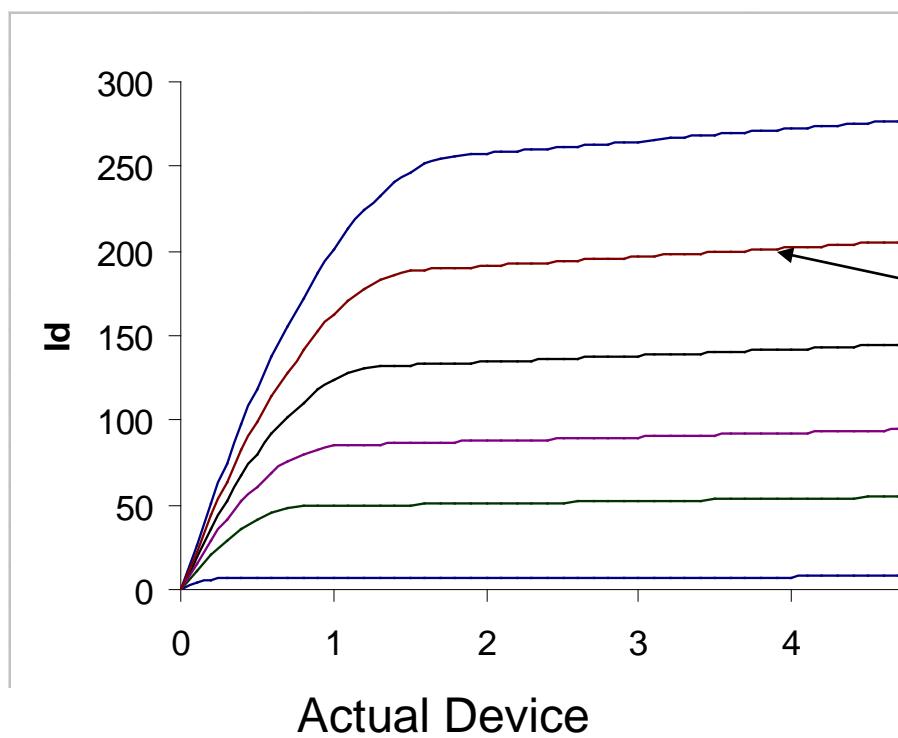
Typical values from -20V to -200V

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Model Extensions

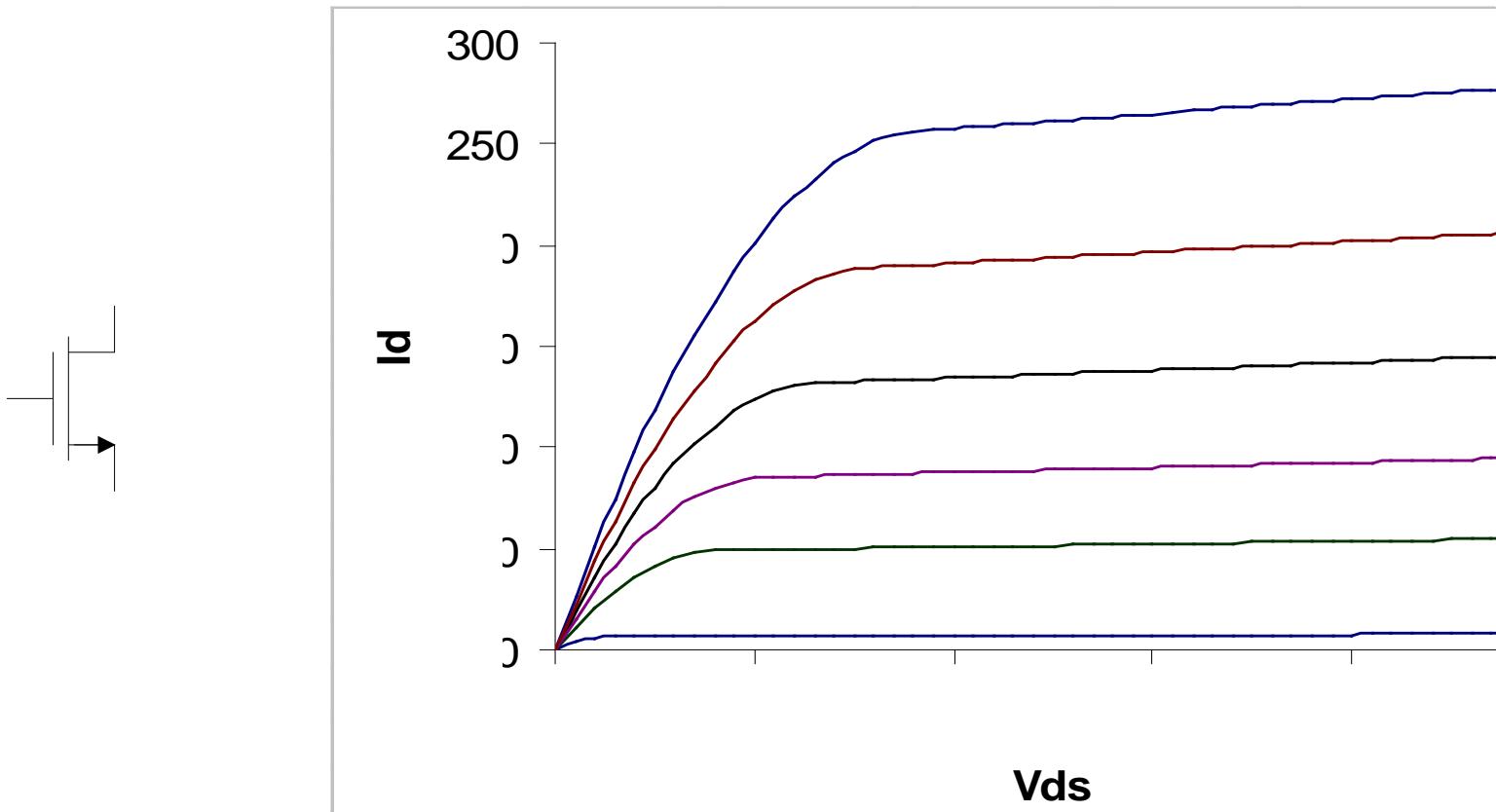


Existing Model



Actual Device

Model Extensions



$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 \bullet (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

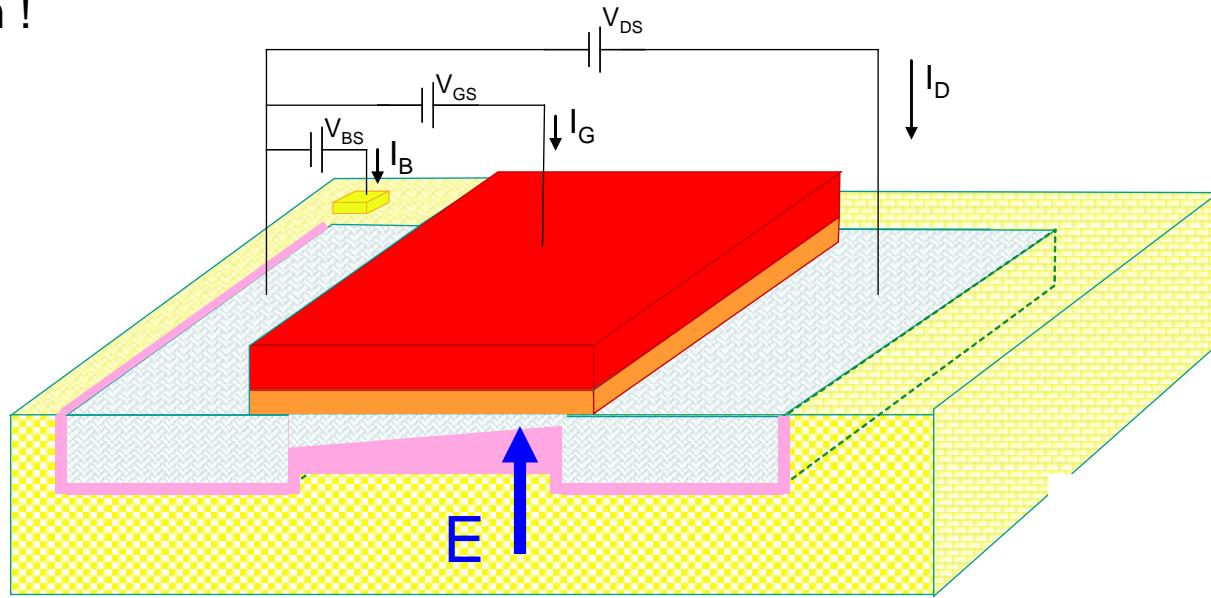
Note: This introduces small discontinuity (not shown) in model at SAT/Triode transition

Further Model Extensions

Existing model does not depend upon the bulk voltage !



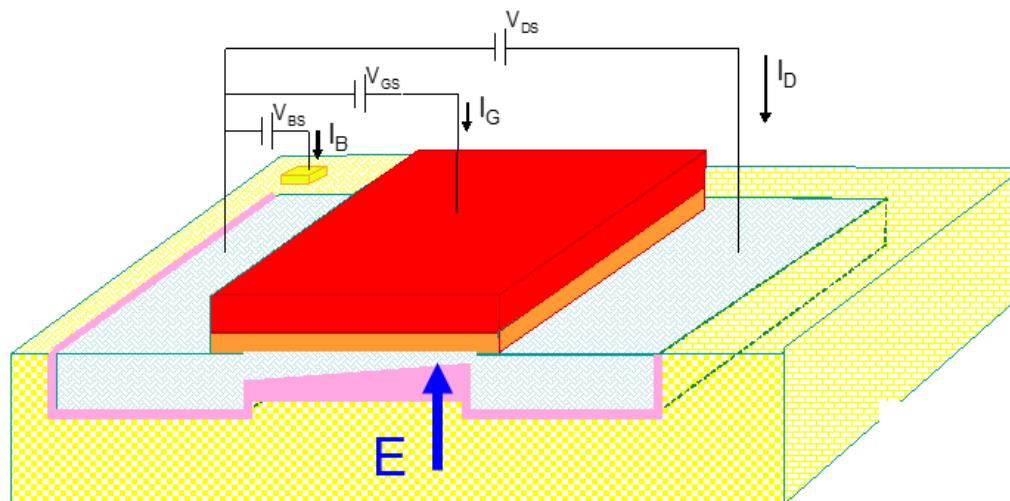
Observe that changing the bulk voltage will change the electric field in the channel region !



Further Model Extensions

Existing model does not depend upon the bulk voltage !

Observe that changing the bulk voltage will change the electric field in the channel region !



Changing the bulk voltage will change the thickness of the inversion layer

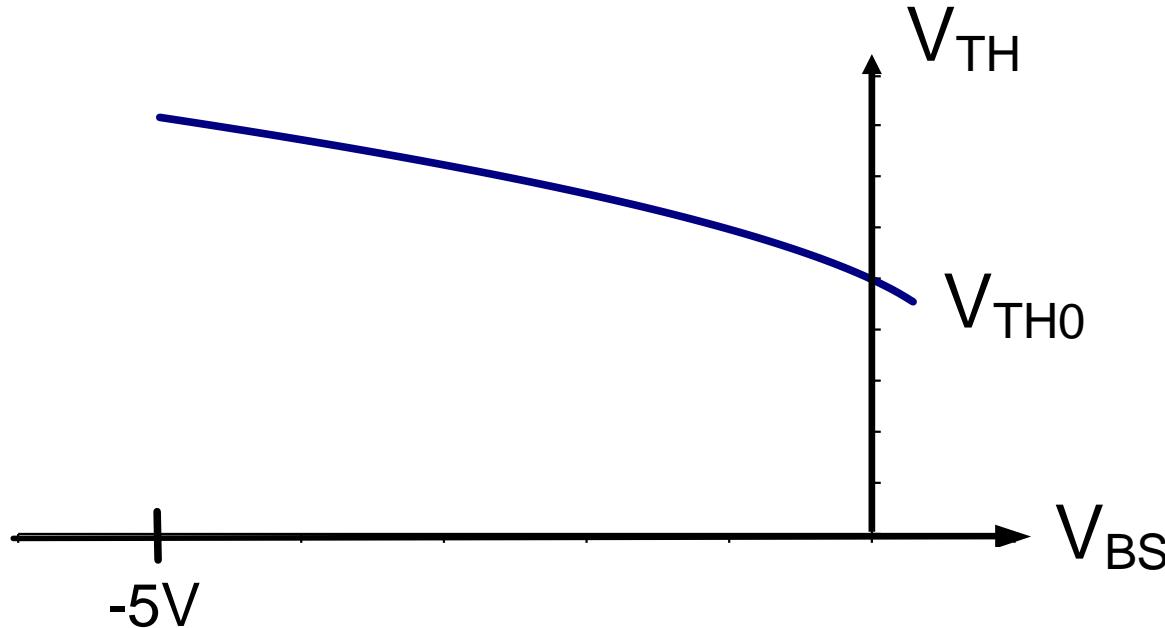
Changing the bulk voltage will change the threshold voltage of the device

$$V_T = V_{T0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \approx 0.4V^{1/2} \quad \phi \approx 0.6V$$

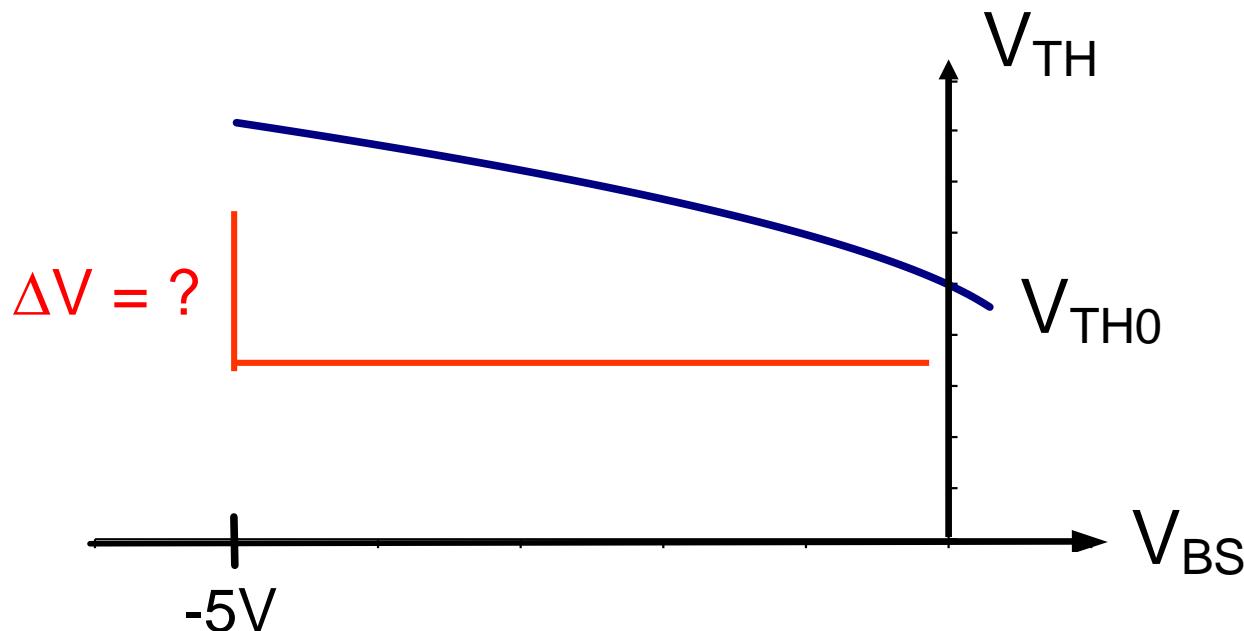


- Bulk-Diffusion Generally Reverse Biased ($V_{BS} < 0$ or at least $V_{BS} < 0.3V$) for n-channel
- Shift in threshold voltage with bulk voltage can be substantial
- Often $V_{BS}=0$

Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \approx 0.4V^{1/2} \quad \phi \approx 0.6V$$



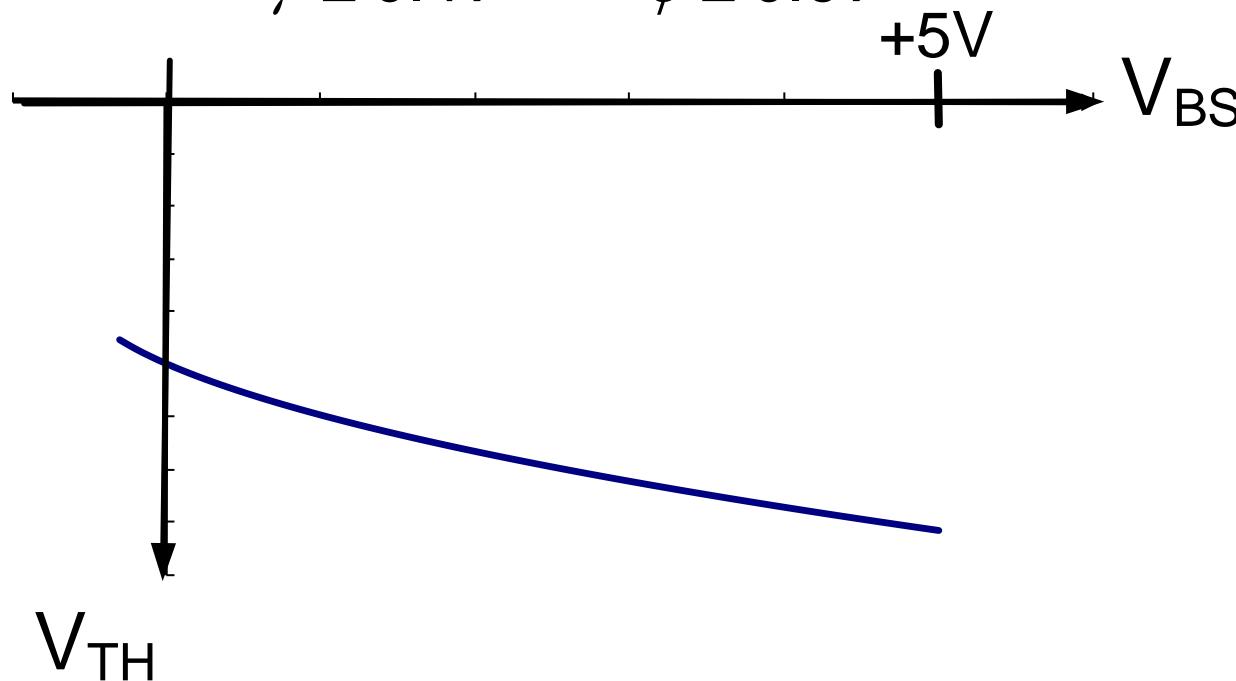
$$\Delta V = V_{TH} - V_{TH0} = \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\Delta V \approx 0.4 \left(\sqrt{0.6V - 5V} - \sqrt{0.6} \right) \approx 0.64V$$

Typical Bulk Effects on Threshold Voltage for p-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \approx 0.4V^{1/2} \quad \phi \approx 0.6V$$



- Bulk-Diffusion Generally Reverse Biased ($V_{BS} > 0$ or at least $V_{BS} > -0.3V$) for p-channel
- Same functional form as for n-channel but $V_{TH0} < 0$
- Magnitude of threshold voltage increases with magnitude of reverse bias

Model Extension Summary

$$I_G = 0$$

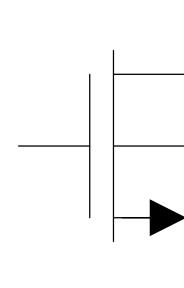
$$I_B = 0$$

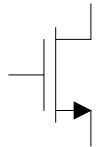
$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 \bullet (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$V_T = V_{T0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

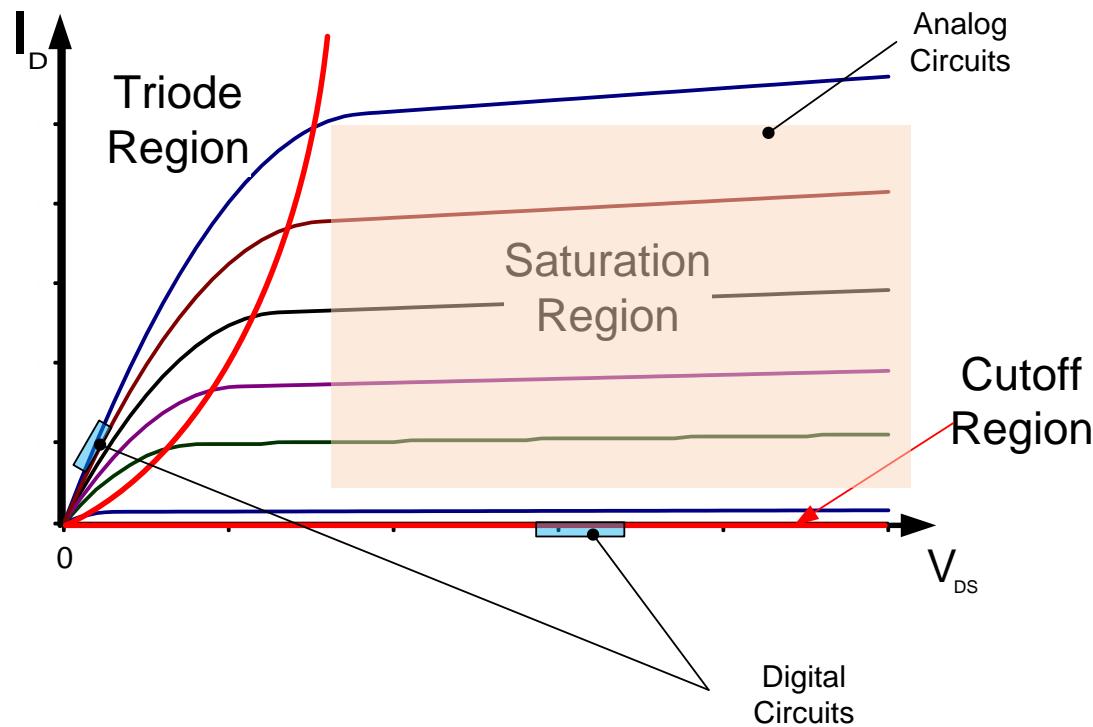
Model Parameters : $\{\mu, C_{ox}, V_{T0}, \phi, \gamma, \lambda\}$

Design Parameters : $\{W, L\}$ but only one degree of freedom W/L





Operation Regions by Applications



Most analog circuits operate in the saturation region

(basic VVR operates in triode and is an exception)

Most digital circuits operate in triode and cutoff regions and switch between these two with Boolean inputs

Model Extension (short devices)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

As the channel length becomes very short, velocity saturation will occur in the channel and this will occur with electric fields around $2V/u$. So, if a gate length is around 1u, then voltages up to 2V can be applied without velocity saturation. But, if gate length decreases and voltages are kept high, velocity saturation will occur

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\alpha} & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \end{cases}$$

α is the velocity saturation index, $2 \geq \alpha \geq 1$

Model Extension (short devices)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\alpha} & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \end{cases}$$

α is the velocity saturation index, $2 \geq \alpha \geq 1$

No longer a square-law model (some term it an α -power model)

For long devices, $\alpha=2$

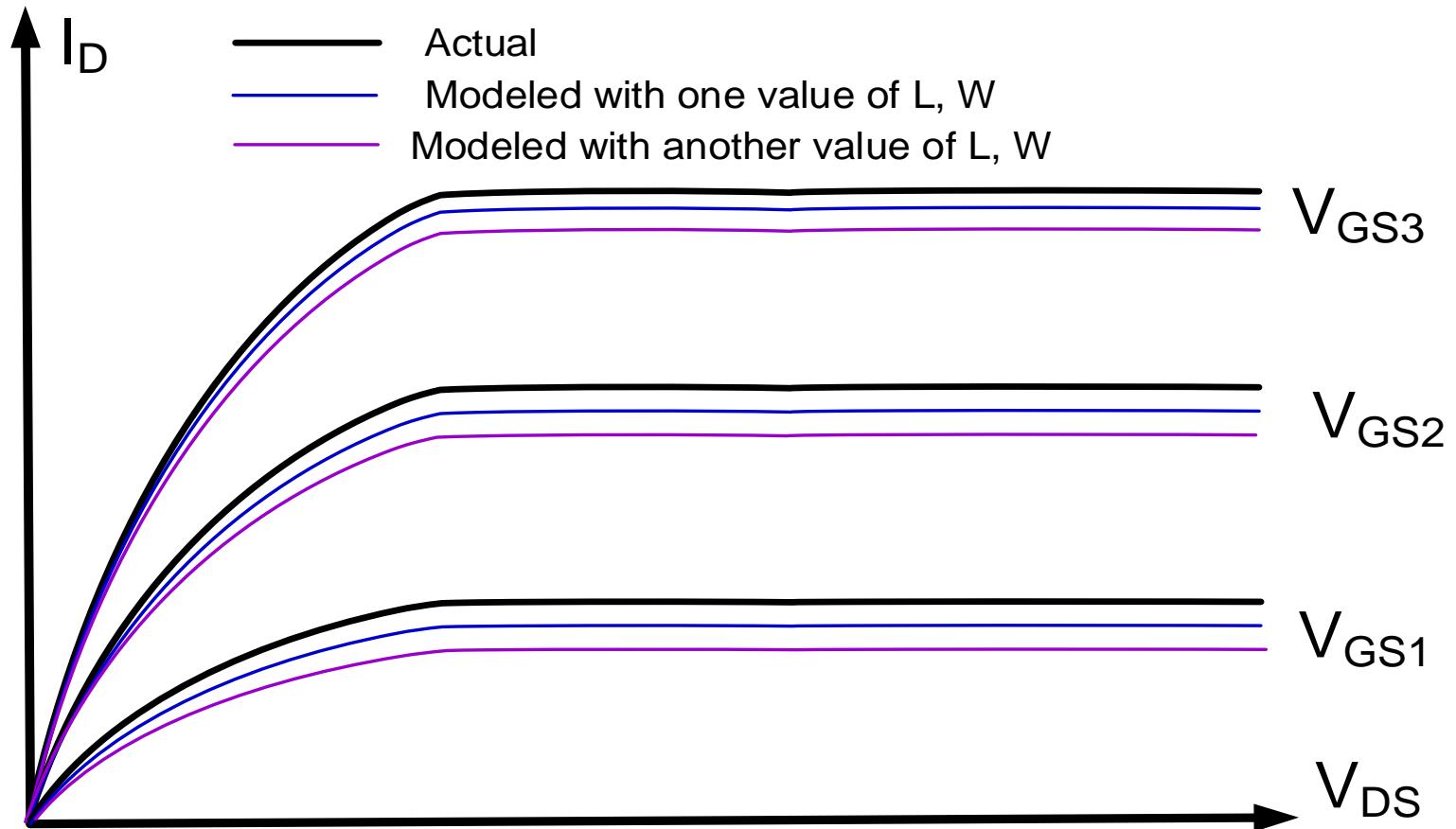
Channel length modulation (λ) and bulk effects can be added to the velocity Saturation as well

Degrading of α is not an attractive limitation of the MOSFET

Model Extension (BSIM model)

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVT0W   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN     = 1
+LLN     = 1
+LWL     = 0
+CGDO    = 2.32E-10
+CJ      = 4.282017E-4
+CJSW    = 3.034055E-10
+CJSWG   = 1.64E-10
+CF      = 0
+PK2     = -0.0289036
*
TNOM    = 27
NCH     = 1.7E17
K2      = -0.09255
W0      = 1.041146E-8
DVT1W   = 0
DVT1    = 0.4232931
UA      = 3.091785E-13
VSAT    = 1.715884E5
B0      = 2.446405E-6
A1      = 8.18159E-7
PRWG    = 0.0328586
WINT    = 2.443677E-7
XW      = 0
VOFF    = -1.493503E-4
CDSC    = 2.4E-4
ETA0    = 2.342963E-3
PCLM    = 2.5941582
PDIBLCB = -0.0431505
PSCBE2  = 3.238266E-4
UTE     = -1.5
KT2     = 0.022
UC1     = -5.6E-11
WLN     = 1
WWL     = 0
LW      = 0
CAPMOD  = 2
CGSO    = 2.32E-10
PB      = 0.9317787
PBSW   = 0.8
PBSWG  = 0.8
PVTH0   = 0.0520855
WKETA   = -0.0237483
LEVEL   = 49
TOX     = 1.42E-8
VTH0    = 0.629035
K3      = 24.0984767
NLX     = 1E-9
DVT2W   = 0
DVT2    = -0.1403765
UB      = 1.702517E-18
A0      = 0.6580918
B1      = 5E-6
A2      = 0.3363058
PRWB   = 0.0104806
LINT    = 6.999776E-8
DWG     = -1.256454E-8
NFACTOR = 1.0354201
CDSCD   = 0
ETAB    = -1.5324E-4
PDIBLC1 = 0.8187825
DROUT   = 0.9919348
PVAG    = 0
KT1     = -0.11
UA1    = 4.31E-9
AT      = 3.3E4
WW     = 0
LL     = 0
LWN    = 1
XPART  = 0.5
CGBO   = 1E-9
MJ      = 0.4495867
MJSW   = 0.1713852
MJSWG  = 0.1713852
PRDSW  = 112.8875816
LKETA  = 1.728324E-3
)
*)
```

Model Errors with Different W/L Values



Binning models can improve model accuracy

BSIM Binning Model

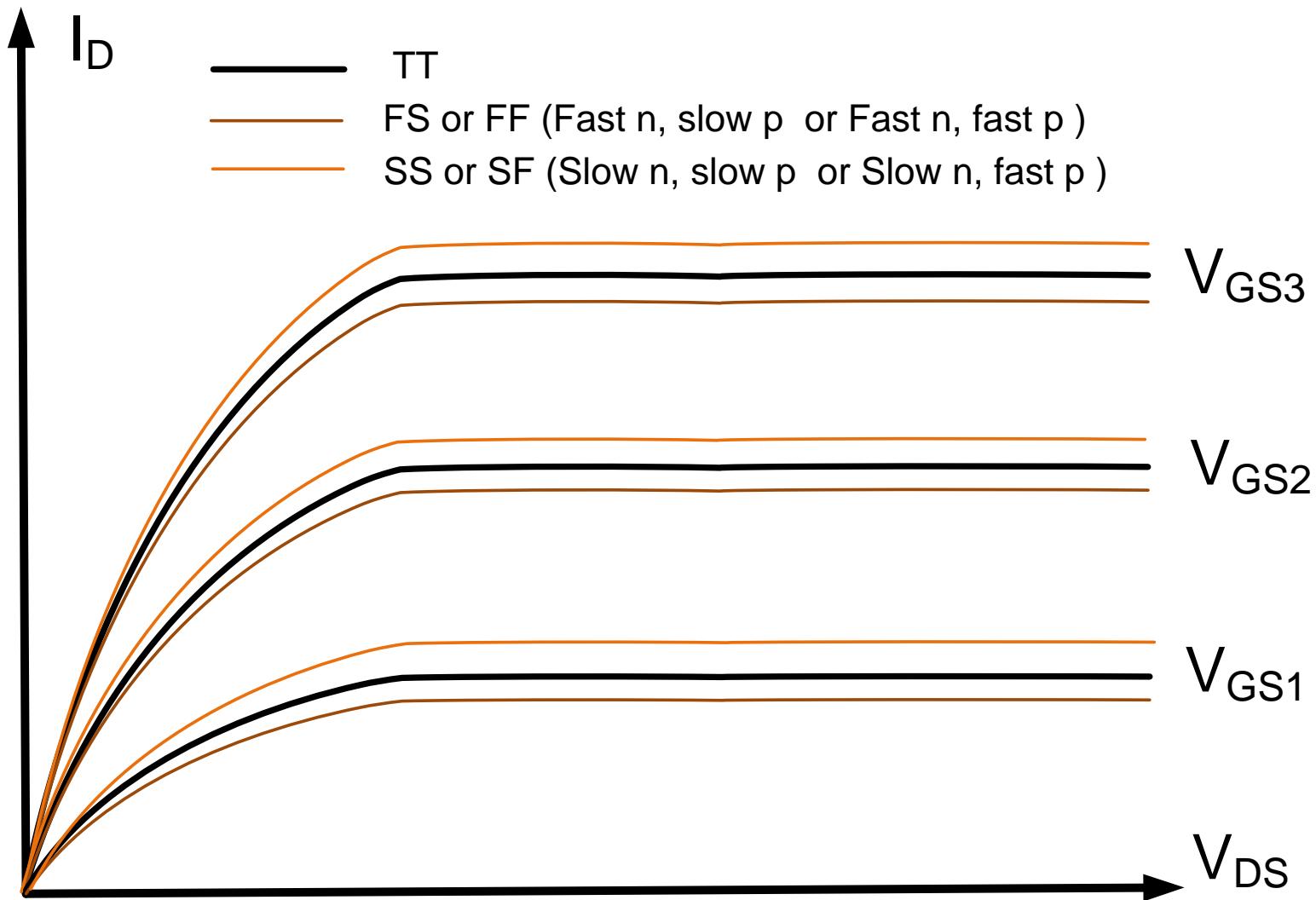
- Bin on device sizes
- multiple BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVT0W   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN    = 1
+LLN    = 1
+LWL    = 0
+CGDO   = 2.32E-10
+CJ      = 4.282017E-4
+CJSW   = 3.034055E-10
+CJSWG  = 1.64E-10
+CF      = 0
+PK2    = -0.0289036
TNOM     = 27
NCH      = 1.7E17
K2       = -0.09255
W0       = 1.041146E-8
DVT1W   = 0
DVT1    = 0.4232931
UA       = 3.091785E-13
VSAT    = 1.715884E5
B0       = 2.446405E-6
A1       = 8.18159E-7
PRWG    = 0.0328586
WINT    = 2.443677E-7
XW       = 0
VOFF    = -1.493503E-4
CDSC    = 2.4E-4
ETA0    = 2.342963E-3
PCLM    = 2.5941582
PDIBLCB = -0.0431505
PSCBE2  = 3.238266E-4
UTE     = -1.5
KT2     = 0.022
UC1     = -5.6E-11
WLN     = 1
WWL     = 0
LW      = 0
CAPMOD  = 2
CGSO    = 2.32E-10
PB      = 0.9317787
PBSW   = 0.8
PBSWG  = 0.8
PVTH0   = 0.0520855
WKETA  = -0.0237483
LEVEL   = 49
TOX     = 1.42E-8
VTH0   = 0.629035
K3      = 24.0984767
NLX     = 1E-9
DVT2W   = 0
DVT2    = -0.1403765
UB      = 1.702517E-18
A0      = 0.6580918
B1      = 5E-6
A2      = 0.3363058
PRWB   = 0.0104806
LINT    = 6.999776E-8
DWG     = -1.256454E-8
NFACTOR = 1.0354201
CDSCD   = 0
ETAB    = -1.5324E-4
PDIBLC1 = 0.8187825
DROUT   = 0.9919348
PVAG    = 0
KT1     = -0.11
UA1    = 4.31E-9
AT      = 3.3E4
WW     = 0
LL     = 0
LWN    = 1
XPART  = 0.5
CGBO   = 1E-9
MJ      = 0.4495867
MJSW   = 0.1713852
MJSWG  = 0.1713852
PRDSW  = 112.8875816
LKETA  = 1.728324E-3
)
```

* With 32 bins, this model has 3040 model parameters !

Model Changes with Process Variations

(n-ch characteristics shown)



Corner models can improve model accuracy

BSIM Corner Models with Binning

- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS

- bin on device sizes

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVTOW   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+DELTAT = 0.01
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN     = 1
+LLN     = 1
+LWL     = 0
+CGDO    = 2.32E-10
+CJ      = 4.282017E-4
+CJSW    = 3.034055E-10
+CJSWG   = 1.64E-10
+CF      = 0
+PK2     = -0.0289036
TNOM    = 27
NCH     = 1.7E17
K2      = -0.09255
W0      = 1.041146E-8
DVT1W   = 0
DVT1    = 0.4232931
UA      = 3.091785E-13
VSAT    = 1.715884E5
B0      = 2.446405E-6
A1      = 8.18159E-7
PRWG    = 0.0328586
WINT    = 2.443677E-7
XW      = 0
VOFF    = -1.493503E-4
CDSC    = 2.4E-4
ETAO    = 2.342963E-3
PCLM    = 2.5941582
PDIBLCB = -0.0431505
PSCBE2  = 3.238266E-4
RSH     = 83.5
UTE     = -1.5
KT2     = 0.022
UC1     = -5.6E-11
WLN     = 1
WWL     = 0
LW      = 0
CAPMOD  = 2
CGSO    = 2.32E-10
PB      = 0.9317787
PBSW    = 0.8
PBSWG   = 0.8
PVTH0   = 0.0520855
WKETA   = -0.0237483
LEVEL   = 49
TOX     = 1.42E-8
VTH0    = 0.629035
K3      = 24.0984767
NLX     = 1E-9
DVT2W   = 0
DVT2    = -0.1403765
UB      = 1.702517E-18
A0      = 0.6580918
B1      = 5E-6
A2      = 0.3363058
PRWB    = 0.0104806
LINT    = 6.999776E-8
DWG     = -1.256454E-8
NFACTOR = 1.0354201
CDSCD   = 0
ETAB    = -1.5324E-4
PDIBLC1 = 0.8187825
DROUT   = 0.9919348
PVAG    = 0
MORMOD  = 1
KT1     = -0.11
UA1     = 4.31E-9
AT      = 3.3E4
WW     = 0
LL      = 0
LWN    = 1
XPART   = 0.5
CGBO    = 1E-9
MJ      = 0.4495867
MJSW    = 0.1713852
MJSWG   = 0.1713852
PRDSW   = 112.8875816
LKETA   = 1.728324E-3
)
```

With 32 size bins and 4 corners, this model has 15,200 model parameters !

End of Lecture 16